MOSFET

Metal Oxide Semiconductor Field Effect Transistor

CoolMOS™ C7

650V CoolMOS™ C7 Power Transistor
IPA65R225C7

Data Sheet

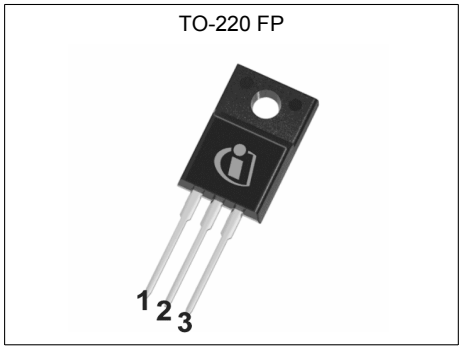
Rev. 2.0
Final

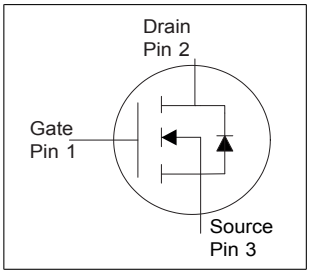
Power Management & Multimarket

1 Description

CoolMOS™ is a revolutionary technology for high voltage power MOSFETs, designed according to the superjunction (SJ) principle and pioneered by Infineon Technologies.

CoolMOS™ C7 series combines the experience of the leading SJ MOSFET supplier with high class innovation. The product portfolio provides all benefits of fast switching superjunction MOSFETs offering better efficiency, reduced gate charge, easy implementation and outstanding reliability.





Features

- Increased MOSFET dv/dt ruggedness
- Better efficiency due to best in class FOM $R_{DS(on)}$*E_{oss} and $R_{DS(on)}$*Q_g
- Best in class $R_{DS(on)}$ /package
- Easy to use/drive
- Pb-free plating, halogen free mold compound
- Qualified for industrial grade applications according to JEDEC (J-STD20 and JESD22)

Benefits

- Enabling higher system efficiency
- Enabling higher frequency / increased power density solutions
- System cost / size savings due to reduced cooling requirements
- Higher system reliability due to lower operating temperatures

Applications

PFC stages and hard switching PWM stages for e.g. Computing, Server, Telecom, UPS and Solar.

Please note: For MOSFET paralleling the use of ferrite beads on the gate or separate totem poles is generally recommended.

Table 1 Key Performance Parameters

Parameter	Value	Unit
V_{DS} @ $T_{j,max}$	700	V
$R_{DS(on),max}$	225	mΩ
$Q_{g.typ}$	20	nC
$I_{D,pulse}$	41	A
E_{oss}@400V	2.3	µJ
Body diode di/dt	55	A/µs

Type / Ordering Code	Package	Marking	Related Links
IPA65R225C7	PG-TO 220 FullPAK	65C7225	see Appendix A

Table of Contents

2 Maximum ratings

at T_j = 25°C, unless otherwise specified

Table 2 Maximum ratings

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Continuous drain current [1]	I_D	- -	- -	7 5	A	T_C=25°C T_C=100°C
Pulsed drain current [2]	$I_{D,pulse}$	-	-	41	A	T_C=25°C
Avalanche energy, single pulse	E_{AS}	-	-	48	mJ	I_D=4.8A; V_{DD}=50V; see table 10
Avalanche energy, repetitive	E_{AR}	-	-	0.24	mJ	I_D=4.8A; V_{DD}=50V; see table 10
Avalanche current, single pulse	I_{AS}	-	-	4.8	A	-
MOSFET dv/dt ruggedness	dv/dt	-	-	100	V/ns	V_{DS}=0...400V
Gate source voltage (static)	V_{GS}	-20	-	20	V	static;
Gate source voltage (dynamic)	V_{GS}	-30	-	30	V	AC (f>1 Hz)
Power dissipation	P_{tot}	-	-	29	W	T_C=25°C
Storage temperature	T_{stg}	-55	-	150	°C	-
Operating junction temperature	T_j	-55	-	150	°C	-
Mounting torque	-	-	-	50	Ncm	M2.5 screws
Continuous diode forward current	I_S	-	-	7	A	T_C=25°C
Diode pulse current[2]	$I_{S,pulse}$	-	-	41	A	T_C=25°C
Reverse diode dv/dt [3]	dv/dt	-	-	1	V/ns	V_{DS}=0...400V, I_{SD}<=I_S, T_j=25°C see table 8
Maximum diode commutation speed	di_f/dt	-	-	55	A/µs	V_{DS}=0...400V, I_{SD}<=I_S, T_j=25°C see table 8
Insulation withstand voltage	V_{ISO}	-	-	2500	V	V_{rms}, T_C=25°C, t=1min

[1] Limited by $T_{j\,max}$.
[2] Pulse width t_p limited by $T_{j,max}$
[3] Identical low side and high side switch with identical R_G

3 Thermal characteristics

Table 3 Thermal characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Thermal resistance, junction - case	R_{thJC}	-	-	4.38	°C/W	-
Thermal resistance, junction - ambient	R_{thJA}	-	-	80	°C/W	leaded
Thermal resistance, junction - ambient for SMD version	R_{thJA}	-	-	-	°C/W	n.a.
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	-	-	260	°C	1.6mm (0.063 in.) from case for 10s

4 Electrical characteristics

at T_j=25°C, unless otherwise specified

Table 4 Static characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Drain-source breakdown voltage	$V_{(BR)DSS}$	650	-	-	V	V_{GS}=0V, I_D=1mA
Gate threshold voltage	$V_{(GS)th}$	3	3.5	4	V	V_{DS}=V_{GS}, I_D=0.24mA
Zero gate voltage drain current	I_{DSS}	- -	- 10	1 -	µA	V_{DS}=650, V_{GS}=0V, T_j=25°C V_{DS}=650, V_{GS}=0V, T_j=150°C
Gate-source leakage current	I_{GSS}	-	-	100	nA	V_{GS}=20V, V_{DS}=0V
Drain-source on-state resistance	$R_{DS(on)}$	- -	0.199 0.478	0.225 -	Ω	V_{GS}=10V, I_D=4.8A, T_j=25°C V_{GS}=10V, I_D=4.8A, T_j=150°C
Gate resistance	R_G	-	1.2	-	Ω	f=1MHz, open drain

Table 5 Dynamic characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input capacitance	C_{iss}	-	996	-	pF	V_{GS}=0V, V_{DS}=400V, f=250kHz
Output capacitance	C_{oss}	-	14	-	pF	V_{GS}=0V, V_{DS}=400V, f=250kHz
Effective output capacitance, energy related [1]	$C_{o(er)}$	-	29	-	pF	V_{GS}=0V, V_{DS}=0...400V
Effective output capacitance, time related [2]	$C_{o(tr)}$	-	313	-	pF	I_D=constant, V_{GS}=0V, V_{DS}=0...400V
Turn-on delay time	$t_{d(on)}$	-	9	-	ns	V_{DD}=400V, V_{GS}=13V, I_D=4.8A, R_G=10Ω; see table 9
Rise time	t_r	-	6	-	ns	V_{DD}=400V, V_{GS}=13V, I_D=4.8A, R_G=10Ω; see table 9
Turn-off delay time	$t_{d(off)}$	-	48	-	ns	V_{DD}=400V, V_{GS}=13V, I_D=4.8A, R_G=10Ω; see table 9
Fall time	t_f	-	10	-	ns	V_{DD}=400V, V_{GS}=13 V, I_D=4.8A, R_G=10Ω; see table 9

Table 6 Gate charge characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gate to source charge	Q_{gs}	-	5	-	nC	V_{DD}=400V, I_D=4.8A, V_{GS}=0 to 10V
Gate to drain charge	Q_{gd}	-	6	-	nC	V_{DD}=400V, I_D=4.8A, V_{GS}=0 to 10V
Gate charge total	Q_g	-	20	-	nC	V_{DD}=400V, I_D=4.8A, V_{GS}=0 to 10V
Gate plateau voltage	$V_{plateau}$	-	5.4	-	V	V_{DD}=400V, I_D=4.8A, V_{GS}=0 to 10V

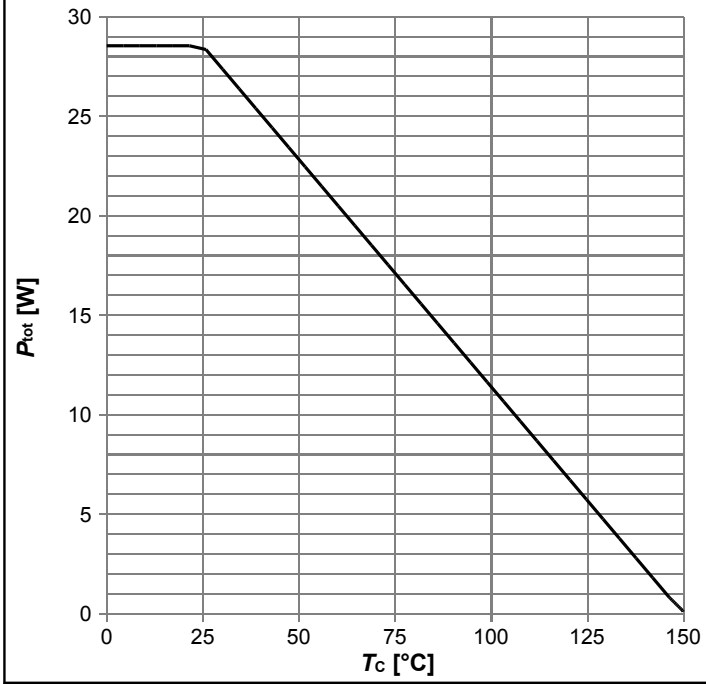
[1] $C_{o(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400V
[2] $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400V

Table 7 Reverse diode characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Diode forward voltage	V_{SD}	-	0.9	-	V	V_{GS}=0V, I_F=4.8A, T_j=25°C
Reverse recovery time	t_{rr}	-	890	-	ns	V_R=400V, I_F=7A, di_F/dt=55A/µs; see table 8
Reverse recovery charge	Q_{rr}	-	6	-	µC	V_R=400V, I_F=7A, di_F/dt=55A/µs; see table 8
Peak reverse recovery current	I_{rrm}	-	16	-	A	V_R=400V, I_F=7A, di_F/dt=55A/µs; see table 8

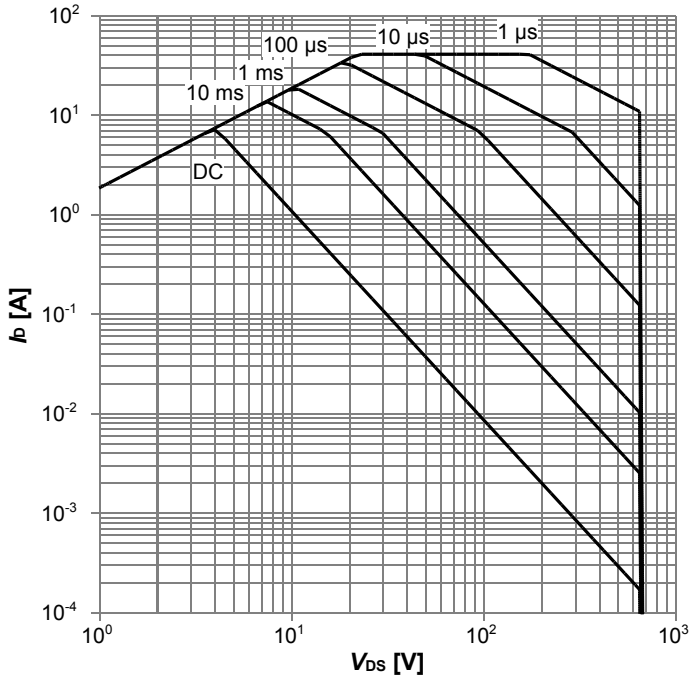
5 Electrical characteristics diagrams

Diagram 1: Power dissipation



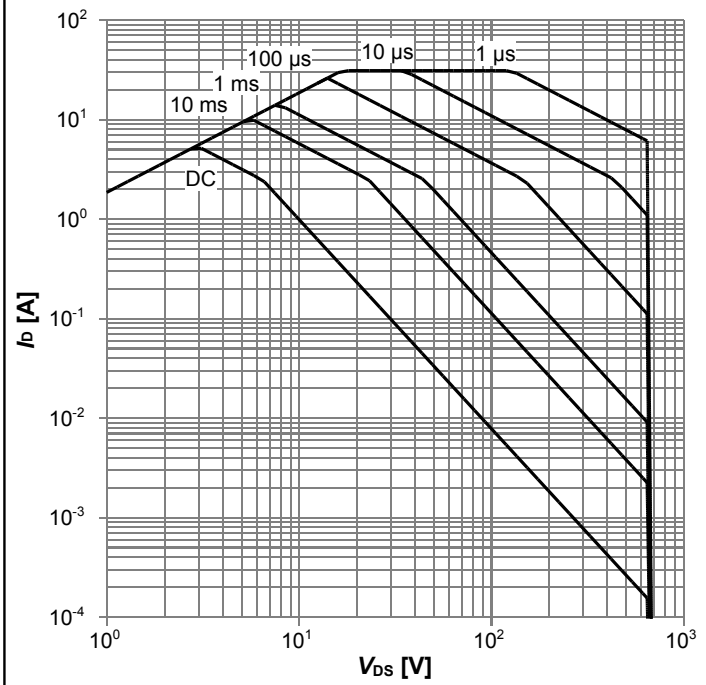
$P_{tot}=f(T_C)$

Diagram 2: Safe operating area



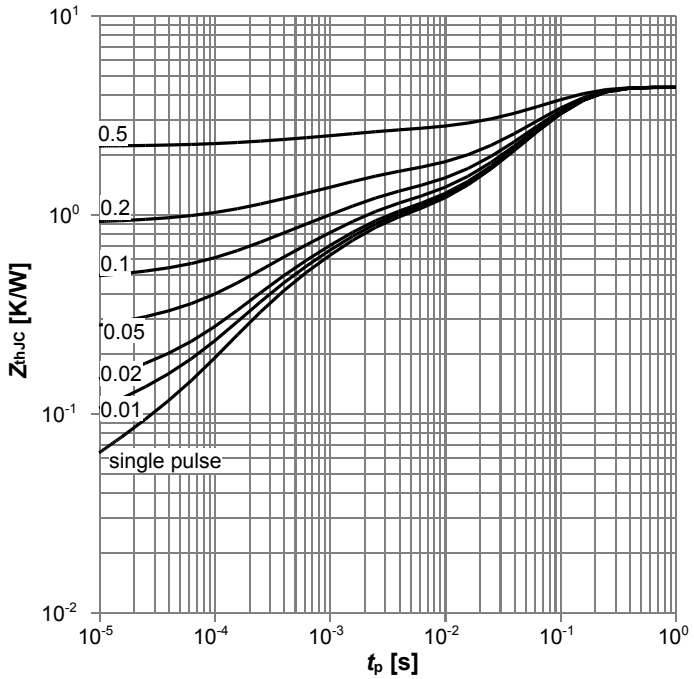
$I_D=f(V_{DS})$; T_C=25 °C; D=0; parameter: t_p

Diagram 3: Safe operating area



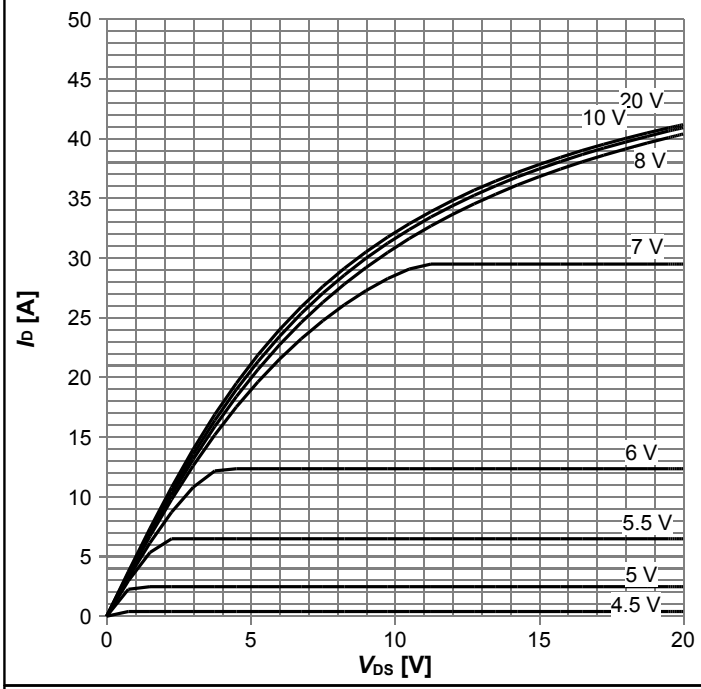
$I_D=f(V_{DS})$; T_C=80 °C; D=0; parameter: t_p

Diagram 4: Max. transient thermal impedance



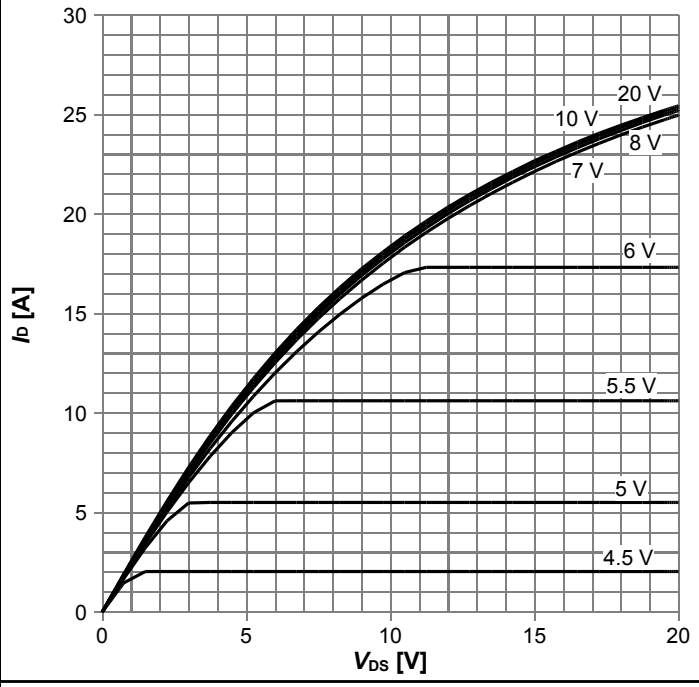
$Z_{thJC}=f(t_P)$; parameter: $D=t_p/T$

Diagram 5: Typ. output characteristics



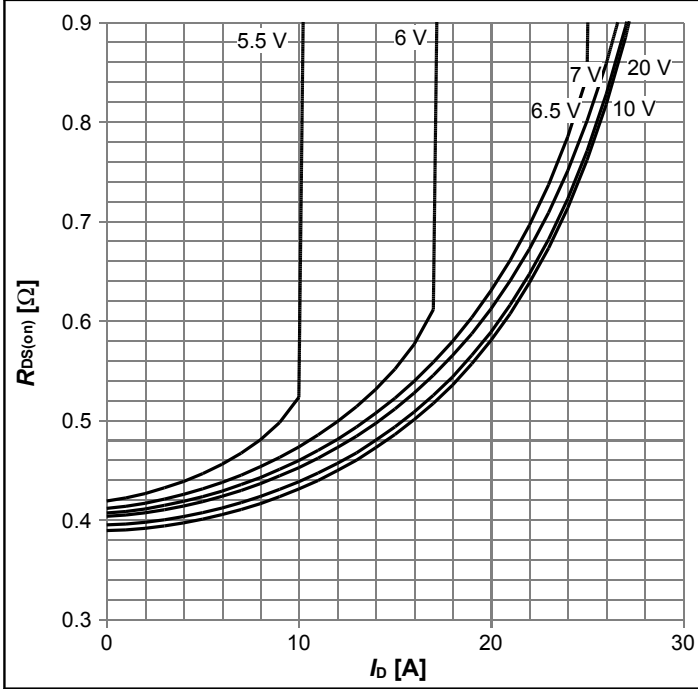
$I_D=f(V_{DS})$; $T_j=25$ °C; parameter: V_{GS}

Diagram 6: Typ. output characteristics



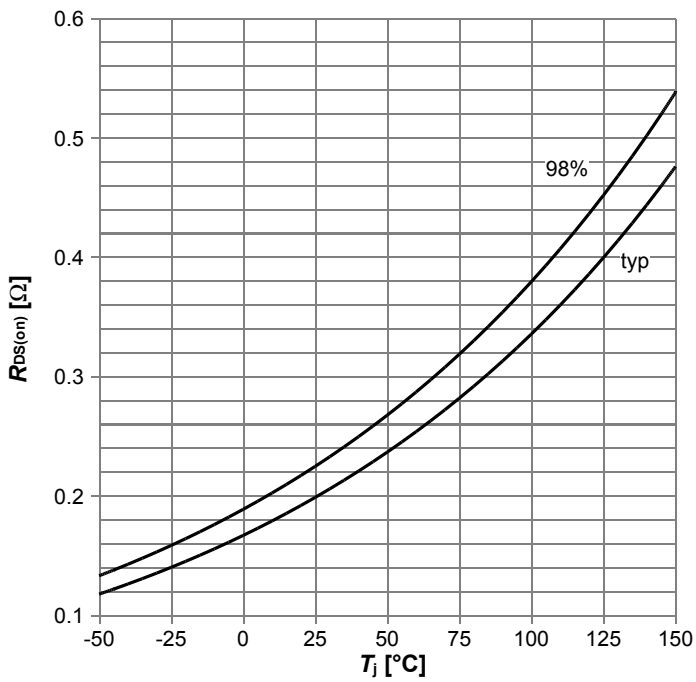
$I_D=f(V_{DS})$; $T_j=125$ °C; parameter: V_{GS}

Diagram 7: Typ. drain-source on-state resistance



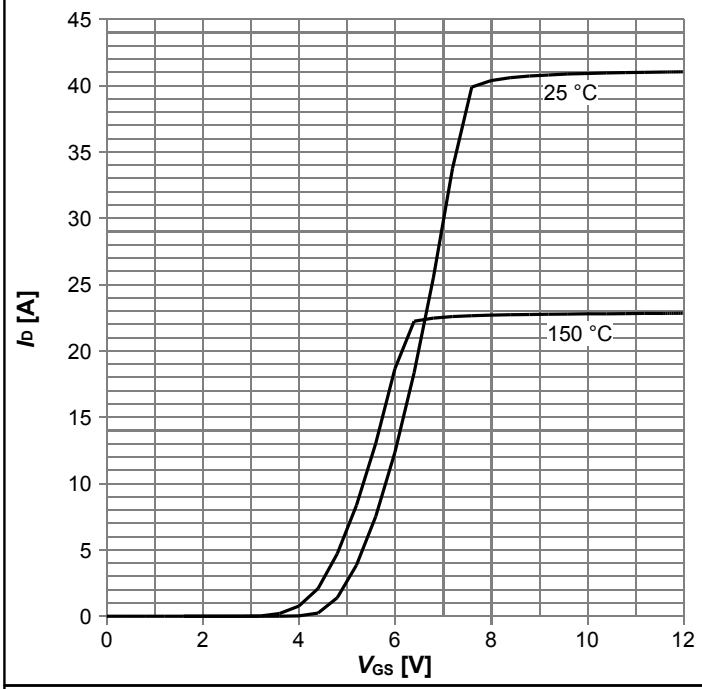
$R_{DS(on)}=f(I_D)$; $T_j=125$ °C; parameter: V_{GS}

Diagram 8: Drain-source on-state resistance



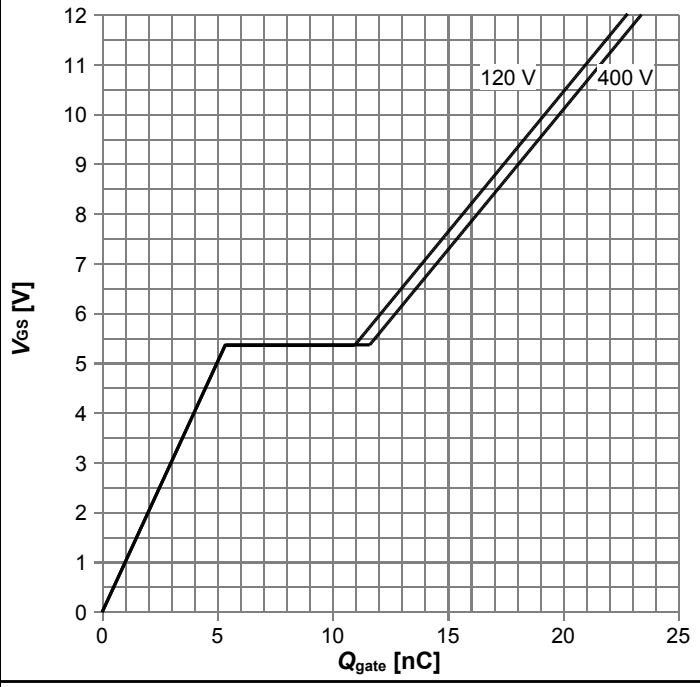
$R_{DS(on)}=f(T_j)$; $I_D=4.8$ A; $V_{GS}=10$ V

Diagram 9: Typ. transfer characteristics



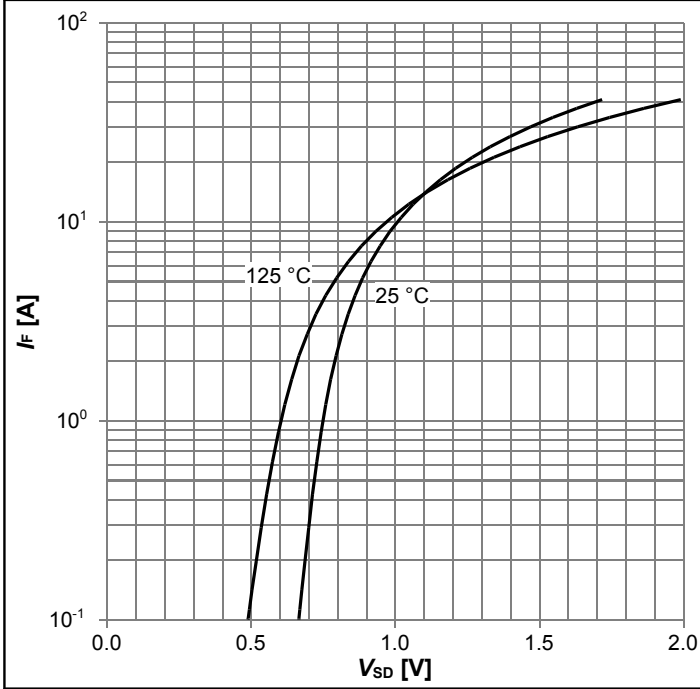
I_D=f(V_{GS}); V_{DS}=20V; parameter: T_j

Diagram 10: Typ. gate charge



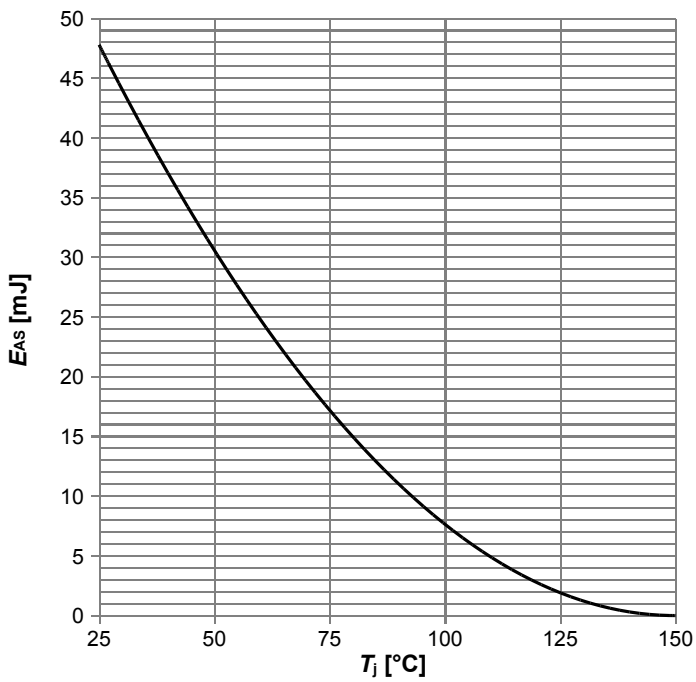
V_{GS}=f(Q_{gate}); I_D=4.8 A pulsed; parameter: V_{DD}

Diagram 11: Forward characteristics of reverse diode



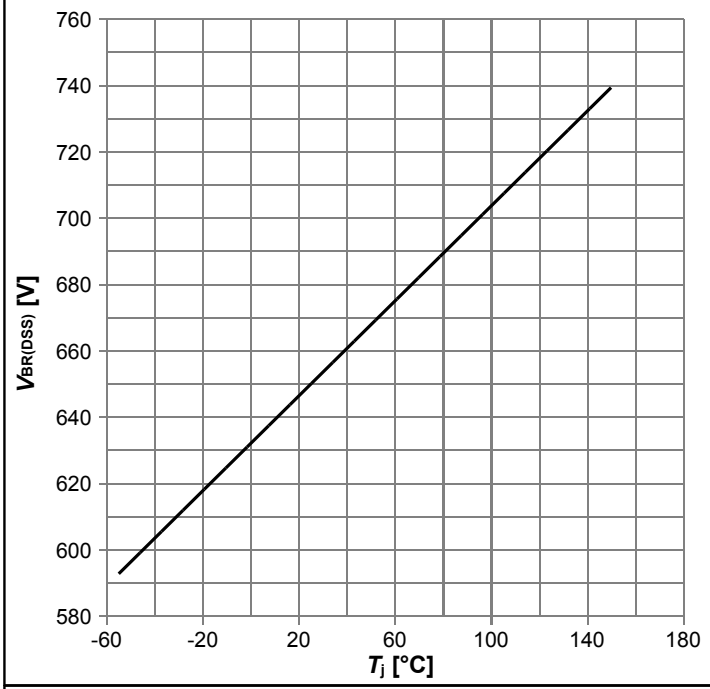
I_F=f(V_{SD}); parameter: T_j

Diagram 12: Avalanche energy



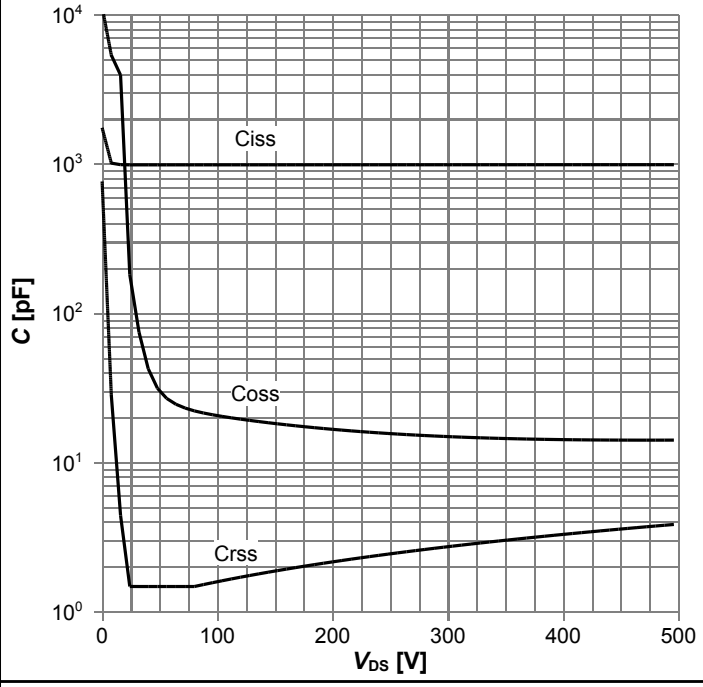
E_{AS}=f(T_j); I_D=4.8 A; V_{DD}=50 V

Diagram 13: Drain-source breakdown voltage



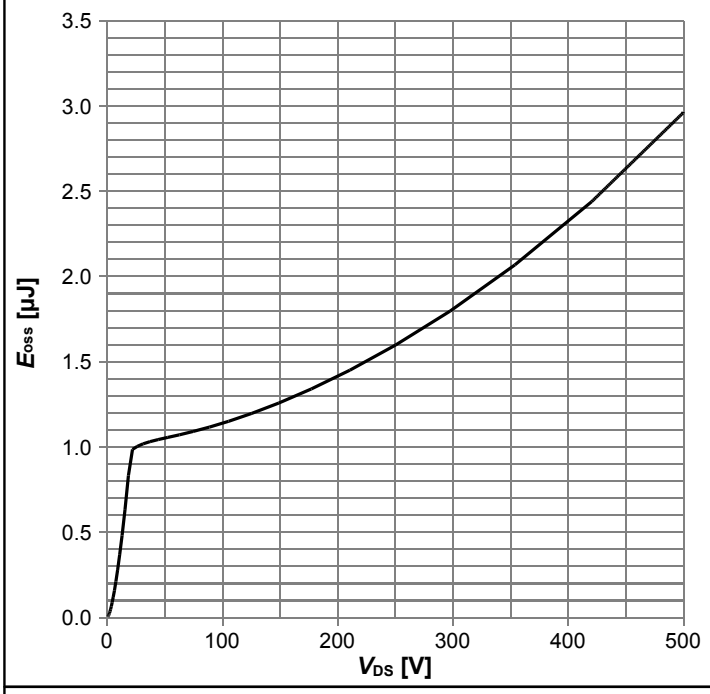
$V_{BR(DSS)}$=f(T_j); I_D=1 mA

Diagram 14: Typ. capacitances



C=f(V_{DS}); V_{GS}=0 V; f=250 kHz

Diagram 15: Typ. Coss stored energy



E_{oss}=f(V_{DS})

6 Test Circuits

Table 8 Diode characteristics

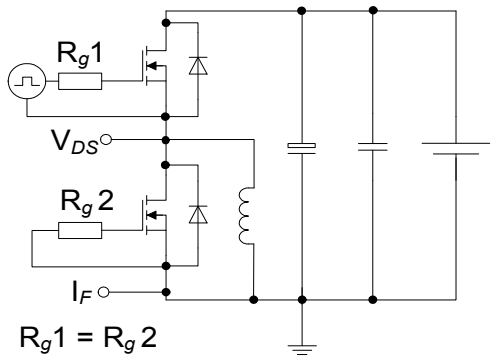
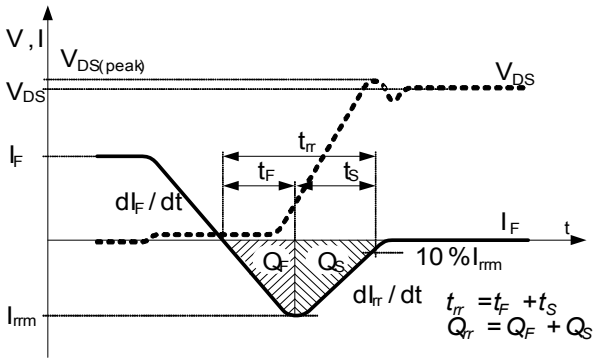
Test circuit for diode characteristics	Diode recovery waveform
	

Table 9 Switching times

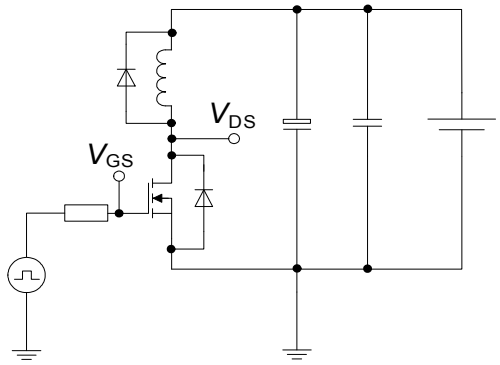
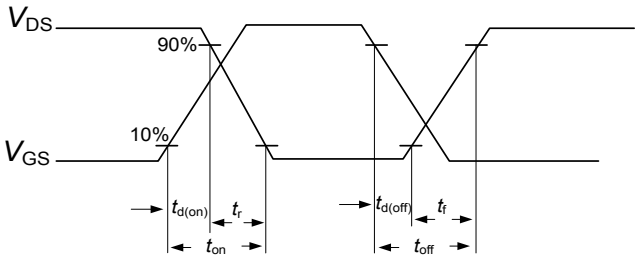
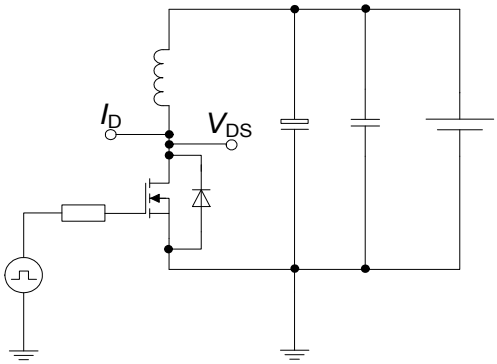
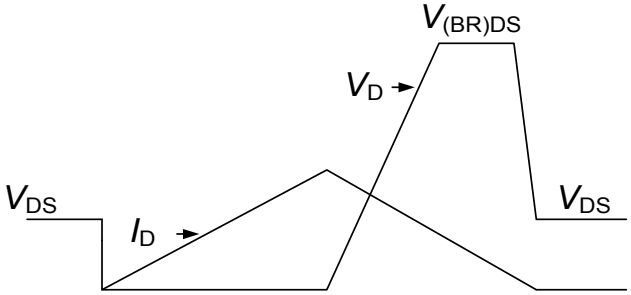
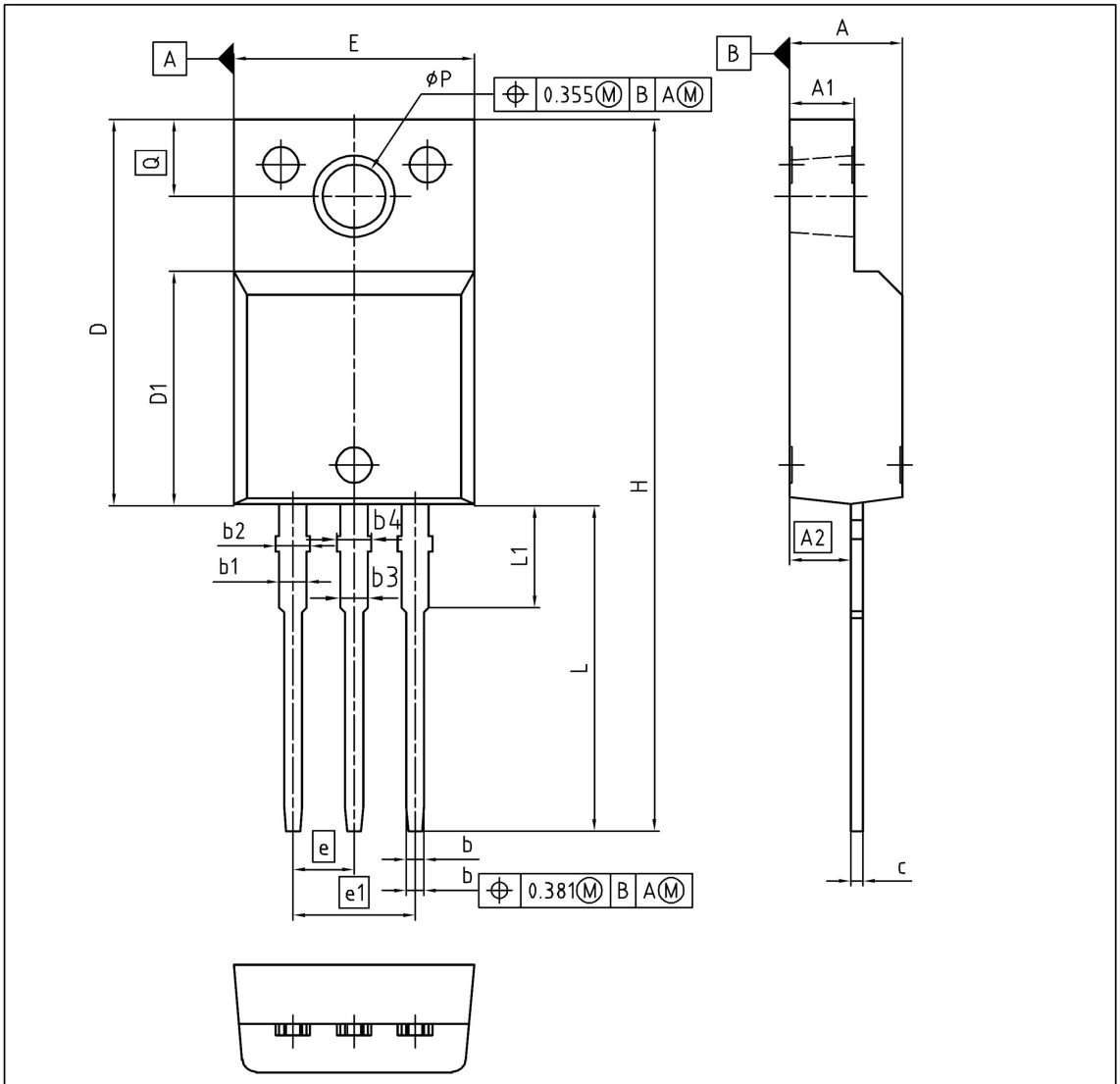
Switching times test circuit for inductive load	Switching times waveform
	

Table 10 Unclamped inductive load

Unclamped inductive load test circuit	Unclamped inductive waveform
	

7 Package Outlines



DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	4.55	4.85	0.179	0.191
A1	2.55	2.85	0.100	0.112
A2	2.42	2.72	0.095	0.107
b	0.65	0.85	0.026	0.033
b1	0.95	1.33	0.037	0.052
b2	0.95	1.51	0.037	0.059
b3	0.65	1.33	0.026	0.052
b4	0.65	1.51	0.026	0.059
c	0.40	0.63	0.016	0.025
D	15.85	16.15	0.624	0.636
D1	9.53	9.83	0.375	0.387
E	10.35	10.65	0.407	0.419
e	2.54		0.100	
e1	5.08		0.200	
N	3		3	
H	29.45	29.75	1.159	1.171
L	13.45	13.75	0.530	0.541
L1	3.15	3.45	0.124	0.136
øP	2.95	3.20	0.116	0.126
Q	3.15	3.50	0.124	0.138

DOCUMENT NO.
Z8B00003319

SCALE 0 2.5 0 2.5 5mm

EUROPEAN PROJECTION

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REVISION
03

Figure 1 Outline PG-TO 220 FullPAK, dimensions in mm/inches

8 Appendix A

Table 11 Related Links

- **IFX CoolMOS™ C7 Webpage:** www.infineon.com
- **IFX CoolMOS™ C7 application note:** www.infineon.com
- **IFX CoolMOS™ C7 simulation model:** www.infineon.com
- **IFX Design tools:** www.infineon.com

Revision History

IPA65R225C7

Revision: 2013-10-22, Rev. 2.0

Previous Revision		
Revision	Date	Subjects (major changes since last revision)
2.0	2013-10-22	Release of final version

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